



Product Specifications

PART NO:

VL383L5621E-B3S-I

REV: 1.0

General Information

2GB 256MX72 DDR SDRAM REGISTERED ECC 184 PIN DIMM

Description The VL383L5621E is a 256Mx72 Double Data Rate SDRAM high density registered DIMM. This memory module consists of thirty-six CMOS 128Mx4 bit with 4 banks DDR Synchronous DRAMs in BGA packages, two 13-26 bit Registered buffers in TSSOP package, a zero delay PLL clock in TSSOP package, and a 2K EEPROM in an 8-pin TSSOP package. This module is a 184-pin dual in-line memory module and is intended for mounting into a connector socket. Decoupling capacitors are mounted on the printed circuit board for each DDR SDRAM.

Features

- . VDD: 2.5V +/- 0.2V VDDQ: 2.5V +/- 0.2V
- . VDDSPD = 2.3V to 3.6V
- . 2.5V I/O (STTL_2 compatible)
- . Supports ECC error detection and correction
- . Two data transfers per clock cycle
- . Bidirectional data strobe (DQS)
- . Differential clock inputs (CK and CK#)
- . DLL aligns DQ and DQS transition with CK transition
- . Programmable Read latency: DDR333(3 clock)
- . Programmable burst; length (2, 4, 8)
- . Programmable burst (sequential & interleave)
- . Auto & self refresh, 7.8us refresh interval (8K/64ms refresh)
- . Serial presence detect (SPD) with EEPROM
- . PCB: Height 1.200", double sided components
- . Gold edge contacts
- . Leadless & lead-free/RoHS compliant
- . Operating temperature (TA): -40°C to +85°C

Pin Name	Function
A0~A12	Address Inputs
BA0, BA1	Bank Select Address
DQ0~DQ63	Data Input/Output
CB0~CB7	Check Bit (Data-in/Data-out)
DQS0~DQS17	Data Strobe Input/Output
CK0, CK0#	Clock Input
CKE0, CKE1	Clock Enable Input
CS0#, CS1#	Chip Select Input
RAS#	Row Address Strobe
CAS#	Column Address Input
WE#	Write Enable
VDD	Power Supply
VDDQ	Power Supply for DQS
VSS	Ground
VREF	Power Supply for Reference
VDDSPD	SPD Power Supply (2.3V-3.6V)
SDA	Serial Data Input/Output
SCL	SPD Clock Input
SA0~SA2	SPD Address
RESET#	Reset Enable
NC	No Connection

Order Information

VL383L5621E-B3 S - I

I: Screening temperature

DRAM MANUFACTURER
S - SAMSUNG

MODULE SPEED
B3: PC2700 @ CL2.5

VL : Lead-free/RoHS



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Pin Configuration

184-PIN DDR DIMM FRONT								184-PIN DDR DIMM BACK							
Pin	Name	Pin	Name	Pin	Name	Pin	Name	Pin	Name	Pin	Name	Pin	Name	Pin	Name
1	VREF	24	DQ17	47	DQS8	70	VDD	93	VSS	116	VSS	139	VSS	162	DQ47
2	DQ0	25	DQS2	48	A0	71	NC	94	DQ4	117	DQ21	140	DQS17	163	NC
3	VSS	26	VSS	49	CB2	72	DQ48	95	DQ5	118	A11	141	A10	164	VDDQ
4	DQ1	27	A9	50	VSS	73	DQ49	96	VDDQ	119	DQS11	142	CB6	165	DQ52
5	DQS0	28	DQ18	51	CB3	74	VSS	97	DQS9	120	VDD	143	VDDQ	166	DQ53
6	DQ2	29	A7	52	BA1	75	CK2#*	98	DQ6	121	DQ22	144	CB7	167	A13*
7	VDD	30	VDDQ	53	DQ32	76	CK2*	99	DQ7	122	A8	145	VSS	168	VDD
8	DQ3	31	DQ19	54	VDDQ	77	VDDQ	100	VSS	123	DQ23	146	DQ36	169	DQS15
9	NC	32	A5	55	DQ33	78	DQS6	101	NC	124	VSS	147	DQ37	170	DQ54
10	RESET#	33	DQ24	56	DQS4	79	DQ50	102	NC	125	A6	148	VDD	171	DQ55
11	VSS	34	vss	57	DQ34	80	DQ51	103	NC	126	DQ28	149	DQS13	172	VDDQ
12	DQ8	35	DQ25	58	VSS	81	VSS	104	VDDQ	127	DQ29	150	DQ38	173	NC
13	DQ9	36	DQS3	59	BA0	82	NC	105	DQ12	128	VDDQ	151	DQ39	174	DQ60
14	DQS1	37	A4	60	DQ35	83	DQ56	106	DQ13	129	DQS12	152	VSS	175	DQ61
15	VDDQ	38	VDD	61	DQ40	84	DQ57	107	DQS10	130	A3	153	DQ44	176	VSS
16	CK1*	39	DQ26	62	VDDQ	85	VDD	108	VDD	131	DQ30	154	RAS#	177	DQS16
17	CK1#*	40	DQ27	63	WE#	86	DQS7	109	DQ14	132	VSS	155	DQ45	178	DQ62
18	VSS	41	A2	64	DQ41	87	DQ58	110	DQ15	133	DQ31	156	VDDQ	179	DQ63
19	DQ10	42	VSS	65	CAS#	88	DQ59	111	CKE1	134	CB4	157	CS0#	180	VDDQ
20	DQ11	43	A1	66	VSS	89	VSS	112	VDDQ	135	CB5	158	CS1#	181	SA0
21	CKE0	44	CB0	67	DQS5	90	NC	113	NC	136	VDDQ	159	DQS14	182	SA1
22	VDDQ	45	CB1	68	DQ42	91	SDA	114	DQ20	137	CK0	160	VSS	183	SA2
23	DQ16	46	VDD	69	DQ43	92	SCL	115	A12	138	CK0#	161	DQ46	184	VDDSPD

Note: *: These pins are not used on this module.



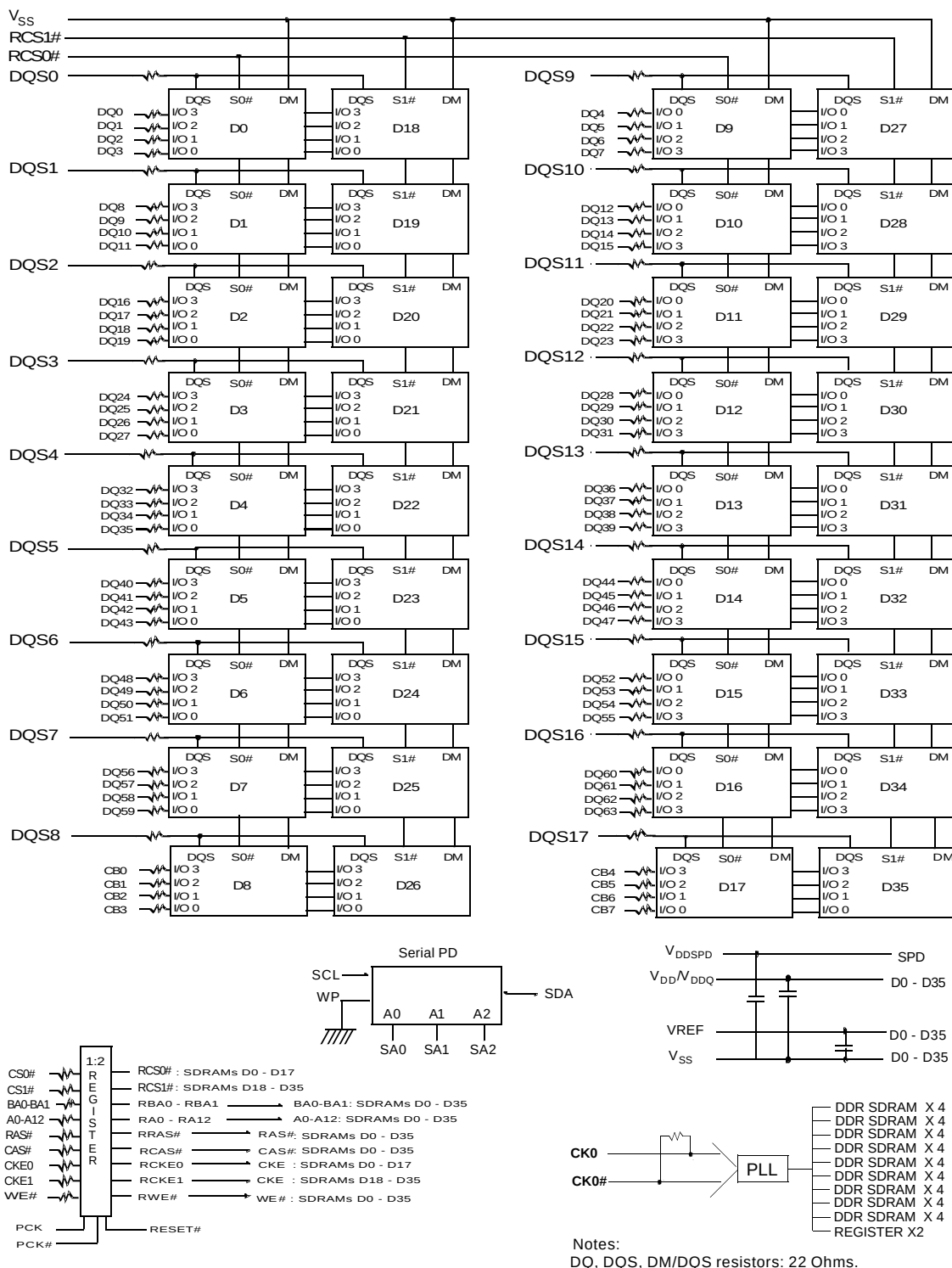
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Functional Block Diagram



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Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Voltage on any pin relative to Vss	V _{IN} , V _{OUT}	-0.5 ~ 3.6	V
Voltage on V _{DD} & V _{DDQ} supply relative to Vss	V _{DD} , V _{DDQ}	-0.1 ~ 3.6	V
Storage temperature	T _{STG}	-55 ~ +150	°C
Operating temperature	T _A	-40 ~ +85	°C
Power Dissipation	P _D	36	W
Short circuit output current	I _{OS}	50	mA

Note: Permanent device damage may occur if ABSOLUTE MAXIMUM RATINGS are exceeded.

Functional operation should be restricted to recommended operating condition.

Exposing to higher than recommended voltage for extended periods of time could affect device reliability.

DC Operating Conditions

T_A = -40°C to +85°C

Parameter		Symbol	Min	Max	Unit	Note
Supply voltage DDR333 (nominal VDD 2.5V)		V _{DD}	2.3	2.7	V	
I/O Supply voltage DDR333 (nominal VDD 2.5V)		V _{DDQ}	2.3	2.7	V	
I/O Reference voltage		V _{REF}	0.49 * V _{DDQ}	0.51 * V _{DDQ}	V	1
I/O Termination voltage		V _{TT}	V _{REF} -0.04	V _{REF} +0.04	V	2
Input logic high voltage		V _{IH} (DC)	V _{REF} +0.15	V _{DDQ} +0.30	V	
Input logic low voltage		V _{IL} (DC)	-0.3	V _{REF} -0.15	V	
Input voltage level, CK and CK#		V _{IN} (DC)	-0.3	V _{DDQ} +0.30	V	
Input differential voltage, CK and CK#		V _{ID} (DC)	0.36	V _{DDQ} +0.60	V	3
Input crossing point voltage, CK and CK#		V _{IX} (DC)	0.3	V _{DDQ} +0.60	V	
Input leakage current	Addr, CAS#,RAS#,WE#	I _I	-5	5	uA	
	CS#, CKE		-5	5	uA	
	CK, CK#		-10	10	uA	
	DM		-4	4	uA	
Output leakage current		I _{OZ}	-10	10	uA	
Output high current(normal strength) V _{OUT} = V + 0.84V		I _{OH}	-16.8	-	mA	
Output high current(normal strength) V _{OUT} = V _{TT} - 0.84V		I _{OL}	16.8	-	mA	
Output high current(half strength) V _{OUT} = V _{TT} + 0.45V		I _{OH}	-9	-	mA	
Output high current(half strength) V _{OUT} = V _{TT} - 0.45V		I _{OL}	9	-	mA	

Notes:

- V_{REF} is expected to be equal to 0.5*V_{DDQ} of the transmitting device, and to track variations in the DC level of the same. Peak to peak noise on V_{REF} may not exceed +/- 2% of the DC value.
- V_{TT} is not applied directly to the device. V_{TT} is a system supply for signal termination resistors, is expected to be set equal to V_{REF}, and must track variations in the DC level of V_{REF}.
- V_{ID} is the magnitude of the difference between the input level on CK and the input level of CK#.



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AC Operating Conditions

(TA = -40°C to +85°C)

Parameter	Symbol	Min	Max	Unit
Input High (Logic1) Voltage	VIH(AC)	VREF+0.31		V
Input Low (Logic0) Voltage	VIL(AC)		VREF-0.31	V
Input Differential Voltage, CK and CK# Inputs	VID(AC)	0.7	VDDQ+0.6	V
Input Crossing Point Voltage, CK and CK# Inputs	VIX(AC)	0.5*VDDQ-0.2	0.5*VDDQ+0.2	V

Input/Output Capacitance

TA=25°C, f=100MHz

Parameter	Symbol	Min	Max	Unit
Input capacitance (A0~A12, BA0~BA1, RAS#, CAS#, WE#)	CIN1	9	11	pF
Input capacitance (CKE0, CKE1)	CIN2	9	11	pF
Input capacitance (CS0#, CS1#)	CIN3	9	11	pF
Input capacitance (CK0, CK0#)	CIN4	11	12	pF
Input/Output capacitance (DQ, DQS, DM, CB)	CIO	11	13	pF



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IDD Specification

(TA = -40°C to +85°C)

Condition	Symbol	-B3	Unit
OPERATING CURRENT: One device bank active; Active-Precharge; $t_{RC}=t_{RC(MIN)}$; $t_{CK}=t_{CK(MIN)}$; DQ,DM and DQS inputs change once per clock cycle; Address and control inputs change once every two clock cycles	IDD0*	2460	mA
OPERATING CURRENT: One device bank; Active-Read-Precharge; BL=4; $t_{RC}=t_{RC(MIN)}$; $t_{CK}=t_{CK(MIN)}$; $I_{OUT}=0mA$; Address and control inputs change once per clock cycle	IDD1*	3000	mA
PRECHARGE POWER-DOWN STANDBY CURRENT: All device banks are idle; Power-down mode; $t_{CK}=t_{CK(MIN)}$; CKE=LOW	IDD2P**	660	mA
IDLE STANDBY CURRENT: CS#=HIGH; All device banks are idle; $t_{CK}=t_{CK(MIN)}$; CKE=HIGH; Address and other control inputs changing once per clock cycle. $V_{IN}=V_{REF}$ for DQ,DQS and DM	IDD2F**	1560	mA
ACTIVE POWER-DOWN STANDBY CURRENT: One device bank active; Power-down mode; $t_{CK}=t_{CK(MIN)}$; CKE=LOW	IDD3P**	1560	mA
ACTIVE STANDBY CURRENT: CS#=HIGH; CKE=HIGH; One device bank active; $t_{RC}=t_{RAS(MAX)}$; $t_{CK}=t_{CK(MIN)}$; DQ,DM and DQS inputs change twice per clock cycle; Address and other control inputs changing once per clock cycle	IDD3N**	2100	mA
OPERATING CURRENT: Burst = 2; Reads; Continuous burst; One device bank active; Address and other control inputs changing once per clock cycle; $t_{CK}=t_{CK(MIN)}$; $I_{OUT}=0mA$	IDD4R*	3090	mA
OPERATING CURRENT: Burst = 2; Writes; Continuous burst; One device bank active; Address and other control inputs changing once per clock cycle; $t_{CK}=t_{CK(MIN)}$; DQ,DM and DQS inputs change twice per clock cycle	IDD4W*	3270	mA
AUTO REFRESH CURRENT: $T_{RC}=T_{RFC(MIN)}$	IDD5**	7860	mA
SELF-REFRESH CURRENT: CKE < 0.2V	IDD6**	180	mA
OPERATING CURRENT: Four device bank interleaving Reads Burst=4 with auto precharge; $t_{RC}=t_{RC(MIN)}$; $t_{CK}=t_{CK(MIN)}$; Address and control inputs change only during Active READ, or WRITE commands	IDD7*	7050	mA
Note: IDD specification is based on Samsung D-die components. *: Value calculated as one module rank in this operation condition, and other module rank in IDD2P (CKE LOW) mode. **: Value calculated as all module ranks in this operation condition.			



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AC Timing Parameters & Specifications

Parameter	Symbol	-B3		Unit
		MIN	MAX	
Row Cycle Time	tRC	60		ns
Refresh row cycle time	tRFC	72		ns
Row active	tRAS	42	70K	ns
RAS# to CAS# delay	tRCD	18		ns
Row precharge time	tRP	18		ns
Row active to row active delay	tRRD	12		ns
Write recovery time	tWR	15		ns
Last data in to READ command	tWTR	1		tCK
Clock cycle time	CL=2	-	-	ns
	CL=2.5	6	12	ns
	CL=3	-	-	ns
Clock high level width	tCH	0.45	0.55	tCK
Clock low level width	tCL	0.45	0.55	tCK
DQS-out access time from CK/CK#	tDQSCK	-0.6	+0.6	ns
Output data access time from CK/CK#	tAC	-0.7	+0.7	ns
Data strobe edge to output data edge	tDQSQ	-	0.4	ns
Read preamble	tRPRE	0.9	1.1	tCK
Read postamble	tRPST	0.4	0.6	tCK
CK to valid DQS-in	tDQSS	0.75	1.25	tCK
DQS-in setup time	tWPRES	0		ns
DQS-in hold time	tWPRE	0.25		tCK
DQS falling edge to CK rising-setup time	tDSS	0.2		tCK
DQS falling edge to CK rising-hold time	tDSH	0.2		tCK
DQS-in high level width	tDQSH	0.35		tCK
DQS-in low level width	tDQSL	0.35		tCK
Address and control input setup time (fast)	tISf	0.75		ns
Address and control input hold time (fast)	tIHf	0.75		ns
Address and control input setup time (slow)	tISs	0.8		ns
Address and control input hold time (slow)	tIHs	0.8		ns
Data-out high impedance time from CK/CK#	tHZ	-0.7	+0.7	ns
Data-out low impedance time from CK/CK#	tLZ	-0.7	+0.7	ns
Mode register set cycle	tMRD	12		ns
DQ & DM setup time to DQS	tDS	0.45		ns
DQ & DM hold time to DQS	tDH	0.45		ns
Control & address input pulse width	tIPW	2.2		ns
DQ & DM input pulse width	tDIPW	1.75		ns
Exit self refresh to non-Read command	tXSNR	75		ns
Exit self refresh to Read command	tXSRD	200		tCK
Refresh interval time	tREFI		7.8	us
Output DQS valid window	tQH	tHP -tQHS	-	ns
Clock half period	tHP	tCLmin or tCHmin	-	ns
Data hold skew factor	tQHS		0.5	ns
DQS write postamble	tWPST	0.4	0.6	tCK
Active Read with auto precharge command	tRAP	18		
Auto precharge Write recovery + Precharge time	tDAL	tWR/tCK + tRP/tCK		tCK



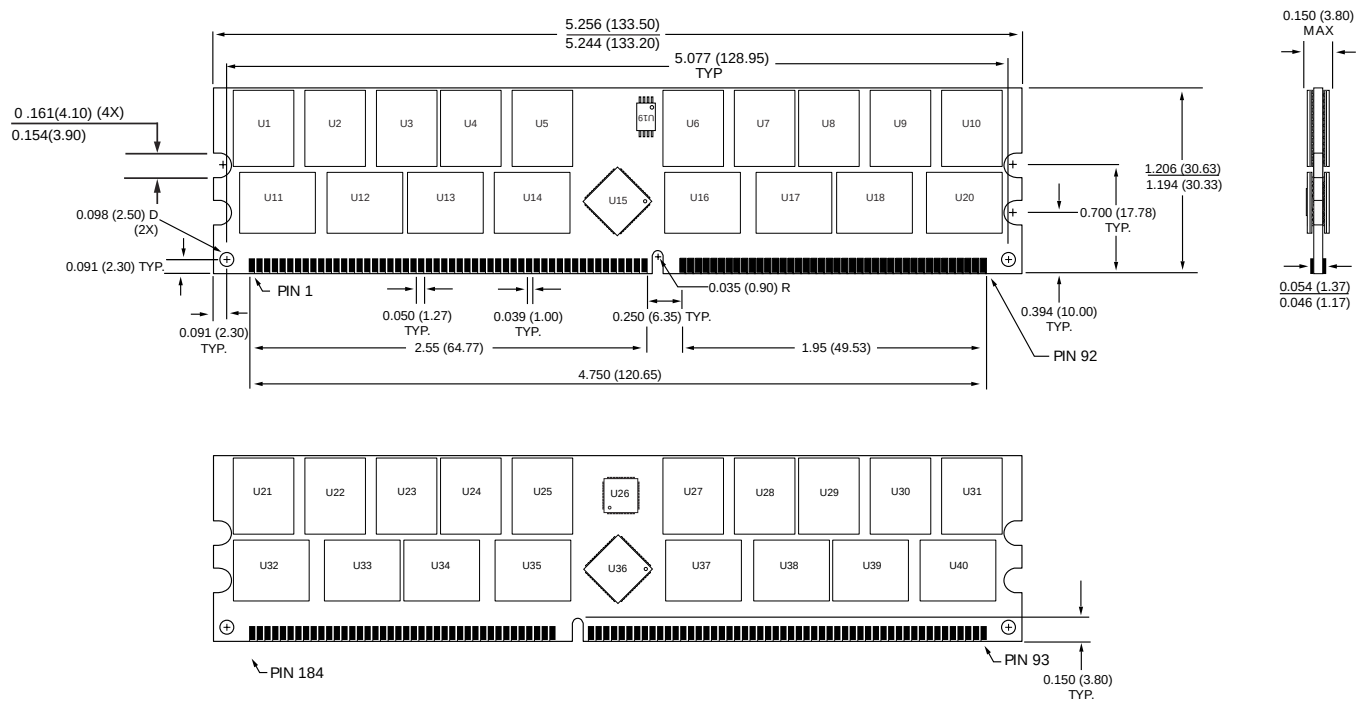
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Package Dimensions



NOTE:

All dimensions in inches (millimeters)



Product Specifications

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Revision History:

Date	Rev.	Page	Changes
07/30/09	1.0	All	Spec release